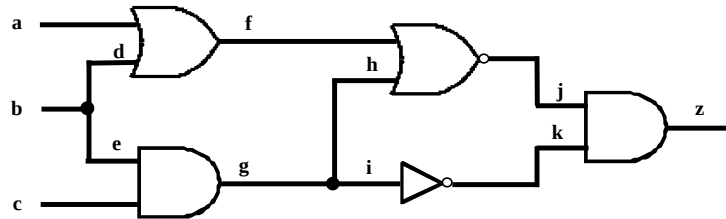


The University of Alabama in Huntsville
ECE Department
CPE 628 01
Fall 2008
Homework #5a Solution

Consider the following circuit.



- Generate all paths in the circuit. How many paths are there in this circuit? The paths are $\uparrow afjz$, $\downarrow afjz$, $\uparrow bdfjz$, $\downarrow bdfjz$, $\uparrow beghjz$, $\downarrow beghjz$, $\uparrow begikz$, $\downarrow begikz$, $\uparrow cghjz$, $\downarrow cghjz$, $\uparrow cgikz$, $\downarrow cgikz$, 12 paths
- Which paths are functionally unsensitizable? $\uparrow cghjz$, $\downarrow cghjz$, $\uparrow cgikz$, $\downarrow cgikz$
- For those sensitizable paths, which ones are robustly testable, and which ones are nonrobustly testable

$\uparrow afjz$	a nc-c d = S0 f nc-c h = S0 j nc-c k = S1 robustly testable	$\uparrow beghjz$	b,e c-nc c = X1 g, h nc-c f = S0 j nc-c k = S1 neither robustly testable nor non-robustly testable	b,e c-nc c = X1 g, h nc-c f = S0 j nc-c k = S1
$\downarrow afjz$	a c-nc d = X0 f c-nc h = X0 j c-nc k = X1 robustly testable	$\downarrow beghjz$	b,e nc-c c = S1 g, h c-nc f = X0 j c-nc k = X1 robustly testable	
$\uparrow bdfjz$	b,d nc-c a = S0 f nc-c h = S0 j nc-c k = S1 robustly testable	$\uparrow begikz$	b, e c-nc c = X1 k nc-c j = S1 neither robustly testable nor non-robustly testable	
$\downarrow bdfjz$	b, d c-nc a = X0 f c-nc h = X0 j c-nc k = X1 robustly testable	$\downarrow begikz$	b, e nc-c c = S1 k c-nc j = X1 robustly testable	

- 4.35 Consider the dictionary of excited and detected stuck-at faults of a test set shown in Table 4.18. Construct the smallest set of vectors that can detect as many transition faults as possible using only these seven stuck-at vectors.

Vectors	Excited Faults	Detected Faults
V ₁	a/0, b/0, c/0, d/0	e/1, f/1
V ₂	c/0, f/0, g/0, h/0	e/1, f/1
V ₃	d/0, e/0, h/0, i/0	a/1, b/1, c/1, f/1, g/1
V ₄	a/0, b/0, g/0, i/0	d/1, e/1, f/1
V ₅	c/0, d/0, g/0	a/1, d/1, h/1, i/1
V ₆	d/0, e/0, i/0	a/1, b/1, c/1, f/1, g/1
V ₇	b/0, g/0	e/1, i/1

Pattern Pair	Delay Faults Detected	Pattern Pair	Delay Faults Detected
V ₁ -V ₂	None	V ₄ -V ₅	a slow-to-fall
V ₂ -V ₃	c slow-to-fall	V ₅ -V ₆	i slow-to-fall
	f slow-to-fall		c slow-to-fall
	g slow-to-fall		g slow-to-fall
V ₃ -V ₄	d slow-to-fall	V ₆ -V ₇	e slow-to-fall
	e slow-to-fall		i slow-to-fall

The faults that remain undetected after applying the seven pattern sequence include:
b stf, h stf, a str, b str, c str, d str, e str, f str, g str, h str, i str , where stf is slow-to-fall
and str is slow-to-rise

For these undetected faults, consider other vector pairs

Pattern Pair	Delay Faults Detected	Pattern Pair	Delay Faults Detected
V ₁ -V ₃	b slow-to-fall	V ₄ -V ₆	b slow-to-fall
V ₁ -V ₄	None	V ₄ -V ₇	None
V ₁ -V ₅	None	V ₅ -V ₁	None
V ₁ -V ₆	b slow-to-fall	V ₅ -V ₂	None
V ₁ -V ₇	None	V ₅ -V ₃	None
V ₂ -V ₁	None	V ₅ -V ₄	None
V ₂ -V ₄	None	V ₅ -V ₇	None
V ₂ -V ₅	h slow-to-fall	V ₆ -V ₁	None
V ₂ -V ₆	None	V ₆ -V ₂	None
V ₂ -V ₇	None	V ₆ -V ₃	None
V ₃ -V ₁	None	V ₆ -V ₄	None
V ₃ -V ₂	None	V ₆ -V ₅	None
V ₃ -V ₅	h slow-to-fall	V ₇ -V ₁	None
V ₃ -V ₆	None	V ₇ -V ₂	None
V ₃ -V ₇	None	V ₇ -V ₃	b slow-to-fall
V ₄ -V ₁	None	V ₇ -V ₄	None
V ₄ -V ₂	None	V ₇ -V ₅	None
V ₄ -V ₃	b slow-to-fall	V ₇ -V ₆	b slow-to-fall

Two pattern pairs are needed to detect the additional two delay faults.

So, use {V₁, V₂, V₃, V₄, V₅, V₆, V₇, V₁, V₃, V₅,}